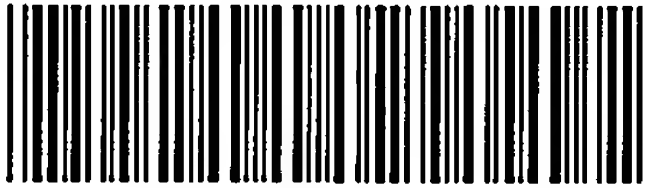


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/662,826	LEE ET AL.	
	Examiner	Art Unit	
	Jia W. Lu	2611	

SEARCHED			
Class	Subclass	Date	Examiner
375	346	11/17/2006	JL
455	278.1	11/17/2006	JL

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
375	346	11/17/2006	JL

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
all east databases	11/17/2006	JL
IEEE Xplore	11/17/2006	JL
Inventorship	11/17/2006	JL